



106th ARFTG Microwave Measurement Conference

Microwave Measurements for Communication and Sensing Technologies

Hollywood, CA | January 18-21, 2026

Co-located with RWW-2026

» Call for Papers | Abstract Due: September 12th, 2025

Suggested topics include, but are not limited to:

- Calibration and measurement techniques for future communication systems, including 6G
- Measurement techniques for sensing applications (e.g. space and autonomous systems)
- Cryogenic measurements for quantum and radio astronomy applications
- Millimeter-wave antennas, OTA testing, and RIS testing
- Microwave measurement techniques applied to AI and other emerging technologies
- Other recent developments in metrology incl. measurement uncertainty

Outstanding exhibition and corporate sponsorship opportunities:

Please contact our Exhibits Chair Joel Dunsmore: exhibits@arftg.org or our Sponsors Chair Chong Li: sponsorship@arftg.org directly for further information.

www.arftg.org

CALL FOR PAPERS

The theme of the 106th ARFTG Conference (co-located with RWW 2026) is **“Microwave Measurements for Communication and Sensing Technologies”**. We invite submissions of original papers showcasing innovative measurement techniques that support the development of future communication and sensing systems. Contributions covering all aspects of RF, microwave, millimeter-wave, and sub-THz measurements are welcome. Suggested topics include, but are not limited to:

- Calibration and measurement techniques for future communication systems incl. 6G
- Measurement techniques for sensing applications (e.g. space and autonomous systems)
- Cryogenic measurements for quantum and radio astronomy applications
- Millimeter-wave antennas, OTA testing, and RIS testing
- Microwave measurement techniques applied to AI and other emerging technologies

Topics always of interest include:

- RF/digital mixed-signal measurement and calibration
- On-wafer calibration and measurements
- Characterization of material properties
- Large signal measurements including linearization of devices, circuits, and systems
- Microwave measurements for biomedical applications
- Other recent developments in metrology incl. measurement uncertainty

DEADLINES

September 12, 2025 Abstract Submission Due

October 10, 2025 Paper acceptance and classification notification

November 3, 2025 Publication-ready paper is due in PDF format

INSTRUCTIONS FOR AUTHORS

Authors are strongly encouraged to use the template on that webpage to prepare both initial paper and final paper submissions.

We request that authors submit an initial paper (4 pages or less) with supporting figures of both experimental setups and measurement results to enable evaluation with respect to the interests of the participants and the novelty of the work.

Contributed papers will be presented as 20-minute talks or in an interactive poster session. Final papers will be published as part of the ARFTG proceedings in IEEE Xplore, provided it has been presented at the conference.

More details can be found on the ARFTG website:

<https://arftg.org/author-instruction>



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